



LexisNexis CourtLink

**Welcome** [Order Documents](#) | [Available Courts](#) | [Total Litigator](#) | [Lexis.com](#) | [Sign Out](#) | [Learning Center](#)  
**Diane**  
**Jackson!**

[My CourtLink](#)  [Search](#)  [Dockets & Documents](#)  [Track](#)  [Alert](#)  [Strategic Profiles](#)  [My Account](#) 



[Search](#) > [Patent Search](#) > [Searching](#)

Patent Search 5717204 8/10/2007 (1)

No cases found.

[Return to Search](#)

(Charges for search still apply)



[About LexisNexis](#) | [Terms & Conditions](#) | [Pricing](#) | [Privacy](#) | [Customer Support](#) - 1-888-311-1966  
Copyright © 2007 LexisNexis®. All rights reserved.

Source: Combined Source Set 10  - Utility, Design and Plant Patents

Terms: patno=5717204 ([Edit Search](#) | [Suggest Terms for My Search](#))

606854 (08) 5717204 February 10, 1998

UNITED STATES PATENT AND TRADEMARK OFFICE GRANTED PATENT

5717204

[Get Drawing Sheet 1 of 20](#)

[Access PDF of Official Patent \\*](#)

[Check for Patent Family Report PDF availability \\*](#)

\* Note: A transactional charge will be incurred for downloading an Official Patent or Patent Family Report. Your acceptance of this charge occurs in a later step in your session. The transactional charge for downloading is outside of customer subscriptions; it is not included in any flat rate packages.

[Order Patent File History / Wrapper from REEDFAX®](#)

[Link to Claims Section](#)

February 10, 1998

Inspecting optical masks with electron beam microscopy

**REISSUE:** February 10, 2000 - Reissue Application filed Ex. Gp.: 2878; Re. S.N. 09/502,534 (O.G. August 1, 2000)

February 10, 2000 - Reissue Application filed Ex. Gp.: 2878; Re. S.N. 09/502,120 (O.G. May 2, 2000)

March 15, 2004 - Reissue Application filed Ex. Gp.: 2878; Re. S.N. 10/801,362 (O.G. September 7, 2004)

**INVENTOR:** Meisburger, Dan - San Jose, California, United States (US); Brodie, Alan D. - Palo Alto, California, United States (US); Chen, Zhong-Wei - San Jose, California, United States (US); Jau, Jack Y. - Fremont, California, United States (US)

**APPL-NO:** 606854 (08)

**FILED-DATE:** February 26, 1996

**GRANTED-DATE:** February 10, 1998

**ASSIGNEE-AT-ISSUE:** KLA Instruments Corporation, San Jose, California, United States (US), United States company or corporation (02)

**LEGAL-REP:** Jones, Allston L.

**PUB-TYPE:** February 10, 1998 - Utility Patent having no previously published pre-grant publication (A)

**PUB-COUNTRY:** United States (US)

**REL-DATA:**

Continuation of Ser. No. 252763, June 2, 1994, ABANDONED

, which is a Continuation-in-part of Ser. No. 889460, May 27, 1992, ABANDONED

**US-MAIN-CL:** 250#310

**US-ADDL-CL:** 250#306, 250#307, 250#397

**CL:** 250

LexisNexis CourtLink

Welcome Diane Jackson!  
[Order Documents](#) | [Available Courts](#) | [Total Litigator](#) | [Lexis.com](#) | [Sign Out](#) | [Learning Center](#)

[My CourtLink](#)  [Search](#)  [Dockets & Documents](#)  [Track](#)  [Alert](#)  [Strategic Profiles](#)  [My Account](#) 



[Search](#) > [Patent Search](#) > Searching

Patent Search 5665968 8/10/2007


No cases found.

[Return to Search](#)

(Charges for search still apply)



[About LexisNexis](#) | [Terms & Conditions](#) | [Pricing](#) | [Privacy](#) | [Customer Support](#) - 1-888-311-1966  
Copyright © 2007 LexisNexis®. All rights reserved.

Source: **Combined Source Set 10**  - **Utility, Design and Plant Patents**  
Terms: **patno=5665968** ([Edit Search](#) | [Suggest Terms for My Search](#))

607191 (08) 5665968 September 9, 1997

UNITED STATES PATENT AND TRADEMARK OFFICE GRANTED PATENT

5665968

[Get Drawing Sheet 1 of 20](#)

[Access PDF of Official Patent \\*](#)

[Check for Patent Family Report PDF availability \\*](#)

\* Note: A transactional charge will be incurred for downloading an Official Patent or Patent Family Report. Your acceptance of this charge occurs in a later step in your session. The transactional charge for downloading is outside of customer subscriptions; it is not included in any flat rate packages.

[Order Patent File History / Wrapper from REEDFAX®](#)

[Link to Claims Section](#)

September 9, 1997

Inspecting optical masks with electron beam microscopy

**INVENTOR:** Meisburger, Dan - San Jose, California, United States (US); Brodie, Alan D. - Palo Alto,, California, United States (US); Chen, Zhong-Wei - San Jose, California, United States (US); Jau, Jack Y. - Fremont, California, United States (US); Grenon, Brian J. - Colchester, Vermont, United States (US)

**APPL-NO:** 607191 (08)

**FILED-DATE:** February 26, 1996

**GRANTED-DATE:** September 9, 1997

**ASSIGNEE-AT-ISSUE:** KLA Instruments Corporation, San Jose, California, United States (US), United States company or corporation (02)

**LEGAL-REP:** Jones, Allston L.

**PUB-TYPE:** September 9, 1997 - Utility Patent having no previously published pre-grant publication (A)

**PUB-COUNTRY:** United States (US)

**REL-DATA:**

Continuation of Ser. No. 252763, June 2, 1994, ABANDONED  
, which is a Continuation-in-part of Ser. No. 889460, May 27, 1992, ABANDONED

**US-MAIN-CL:** 250#310

**US-ADDL-CL:** 250#306, 250#307

**CL:** 250

**SEARCH-FLD:** 250#310, 250#306, 250#307

**IPC-MAIN-CL:** [6] H01J 037#26

## Extended Family Search Results

**US5717204/PN Results : 7**

### PATENT FAMILY


#	Patent No.	Kind	Date	Applic.No.	Date
1)	JP06188294	A	19940708	1993JP-0124458	19930526
	JP3730263	B2	20051221		
2)	JP08068772	A	19960312	1995JP-0126723	19950525
3)	JP2002250707	A	20020906	2001JP-0361084	20011127
4)	JP2003215067	A	20030730	2002JP-0322535	20021106
5)	US5578821	A	19961126	1995US-0371458	19950111
6)	US5717204	A	19980210	1996US-0606854	19960226
7)	US5665968	A	19970909	1996US-0607191	19960226

### Priority :

1992US-0889460	19920527
1994US-0252763	19940602
1995US-0371458	19950111
1996US-0606854	19960226
1996US-0607191	19960226



1 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

PN -  JP6188294 A 19940708 [JP06188294]

STG - (A) Doc. Laid open to publ. Inspec.

TI - (A) EQUIPMENT AND METHOD OF AUTOMATIC SUBSTRATE INSPECTION USING CHARGED PARTICLE BEAM

PA - (A) KLA INSTR CORP

PA0 - (A) KLA INSTR CORP

IN - (A) DAN MAISUBAAGAA; ARAN DEII BUROODEII; ANIRU EE DESAI; DENISU JII EMUGE; TSUON UEI CHIEN; RICHIYAADO SHIMONZU; DEEBU II EE SUMISU; EIPURIRU DATSUTA; JIEI KAAKUUTSUDO EICHI RAFU; RESURII EE HONFUI; HENRII PIASU PAASHI; JIYON MAKUMAATORII; ERITSUKU MANROO

IN0 - (A) MEISBERGER DAN; BRODIE ALAN D; DESAI ANIL A; EMGE DENNIS G; CHEN ZHONG-WEI; SIMMONS RICHARD; SMITH DAVE E A; DUTTA APRIL; ROUGH J KIRKWOOD H; HONFI LESLIE A; PEARCE-PERCY HENRY; MCMURTRY JOHN; MUNRO ERIC

IC - (A) G01R-031/302 H01L-021/66

PN2 - JP3730263 B2 20051221 [JP3730263]

STG2 - (B2) Grant. Pat. With A from 2500000 on


IC2 - (B2) G01R-031/302 H01L-021/66

**AP** - JP12445893 19930526 [1993JP-0124458]  
**PR** - US88946092 19920527 [1992US-0889460]  
**ICAA** - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]  
**ICCA** - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]  
**FI** - G01R31/28 L; H01L21/66 C  
**FTM** - 4M106 AA01; 4M106 AA09; 4M106 BA02; 4M106 DB05; 4M106 DJ21; 4M106 DJ18;  
 2G032 AA01; 2G032 AC02; 2G032 AC03; 2G032 AF04; 2G032 AF08; 2G032 AH01;  
 2G032 AH02; 2G032 AL00; 2G132 AA00; 2G132 AC02; 2G132 AC03; 2G132 AE01;  
 2G132 AE22; 2G132 AF12; 2G132 AF13; 2G132 AL12; 2G132 AL09; 2G132 AE16




---


2 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

**PN** -  JP8068772 A 19960312 [JP08068772]  
**STG** - (A) Doc. Laid open to publ. Inspec.  
**TI** - (A) APPARATUS AND METHOD FOR AUTOMATIC MASK INSPECTION BY USING ELECTRON BEAM MICROSCOPY  
**PA** - (A) KLA INSTR CORP  
**PA0** - (A) KLA INSTR CORP  
**IN** - (A) DAN MAISUBAAGAA; ARAN DEII BUROODEII; TSUON UEI CHIEN; JIYATSUKU WAI JIYOO; BURAIAN JIEI GURENON  
**IN0** - (A) DAN MEISBERGER; ALAN D BROADY; TSUON UEI CHIEN; JACK Y JOE; BRIAN J GLENNON  
**IC** - (A) G01M-011/00 G01N-023/203 G01N-023/225 G21K-005/04 H01J-037/28 H01L-021/66  
**AP** - JP12672395 19950525 [1995JP-0126723]  
**PR** - US25276394 19940602 [1994US-0252763]  
**ICAA** - G01M-011/00 [2006-01 A - I R M EP]; G01N-023/203 [2006-01 A - I R M EP]; G01N-023/225 [2006-01 A - I R M EP]; G21K-005/04 [2006-01 A - I R M EP]; H01J-037/28 [2006-01 A - I R M EP]; H01L-021/66 [2006-01 A - I R M EP]  
**ICCA** - G01M-011/00 [2006 C - I R M EP]; G01N-023/20 [2006 C - I R M EP]; G01N-023/22 [2006 C - I R M EP]; G21K-005/04 [2006 C - I R M EP]; H01J-037/28 [2006 C - I R M EP]; H01L-021/66 [2006 C - I R M EP]  
**FI** - G01N23/203; G01N23/225; G21K5/04 E; G01M11/00 T; H01L21/66 J; H01J37/28 C; H01J37/28 B; G03F1/08 S  
**FTM** - 2G001 AA03; 2G001 BA07; 2G001 BA15; 2G001 BA29; 2G001 CA03; 2G001 DA01; 2G001 FA06; 2G001 JA01; 2G001 JA15; 2G001 LA11; 2G001 RA03; 2G001 RA08; 2G001 RA20; 2G086 CC05; 2G086 GG01; 2G086 HH05; 2G086 HH06; 4M106 AA01; 4M106 AA09; 4M106 AA11; 4M106 BA02; 4M106 CA39; 4M106 CA41; 4M106 DE01; 4M106 DE08; 4M106 DE20; 4M106 DJ18; 4M106 DJ20; 4M106 DJ21; 5C033 UU01; 5C033 UU04; 5C033 UU05; 5C033 UU08; 2H095 BB03; 2H095 BD02; 2H095 BD14; 2H095 BA10; 2H095 BC16




---

3 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

**PN** -  JP2002250707 A 20020906 [JP2002250707]  
**STG** - (A) Doc. Laid open to publ. Inspec.  
**TI** - (A) DEVICE AND METHOD FOR AUTOMATICALLY INSPECTING SUBSTRATE

## USING CHARGED PARTICLE BEAM

PA - (A) KLA INSTR CORP

IN - (A) BRODIE ALAN D; DUTTA APRIL; EMGE DENNIS G; MCMURTRY JOHN; CHEN ZHONG-WEI; DESAI ANIL A; HONFI LESLIE A; MEISBERGER DAN; MUNRO ERIC; SIMMONS RICHARD; SMITH DAVE E A; PEARCE-PERCY HENRY; ROUGH J KIRKWOOD H

IC - (A) G01N-023/04 G01N-023/203 G01N-023/225 G01R-031/28 G01R-031/302 G03F-001/08 G03F-001/16 H01L-021/027 H01L-021/66

AP - JP2001361084 20011127 [2001JP-0361084]

PR - US88946092 19920527 [1992US-0889460]

ICAA - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]

ICCA - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]


FI - G01N23/225; G01N23/04; G01N23/203; G01R31/28 M; G01R31/28 L; G03F1/08 S; G03F1/16 F; H01L21/66 J; H01L21/30 502V

FTM - 2G001 AA03; 2G001 AA09; 2G001 BA07; 2G001 BA11; 2G001 BA15; 2G001 CA03; 2G001 FA06; 2G001 GA01; 2G001 GA06; 2G001 GA13; 2G001 HA13; 2G001 JA02; 2G001 JA03; 2G001 JA13; 2G001 KA03; 2G001 LA11; 2G001 MA05; 2G001 PA01; 2G001 PA02; 2G001 PA13; 2G132 AA00; 2G132 AD15; 2G132 AE16; 2G132 AE22; 2G132 AF12; 2G132 AL09; 2G132 AL11; 2H095 BA10; 2H095 BD04; 2H095 BD14; 2H095 BD27; 4M106 AA01; 4M106 BA02; 4M106 CA39; 4M106 DB05; 4M106 DB20; 4M106 DJ18; 4M106 DJ20

UP - 2002-41



## 4 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

PN -  JP2003215067 A 20030730 [JP2003215067]

STG - (A) Doc. Laid open to publ. Inspec.

TI - (A) SYSTEM AND METHOD FOR AUTOMATICALLY INSPECTING SUBSTRATE USING CHARGED PARTICLE BEAM

PA - (A) KLA INSTR CORP

IN - (A) BRODIE ALAN D; DUTTA APRIL; EMGE DENNIS G; MCMURTRY JOHN; CHEN ZHONG-WEI; DESAI ANIL A; HONFI LESLIE A; MEISBERGER DAN; MUNRO ERIC; SIMMONS RICHARD; SMITH DAVE E A; PEARCE-PERCY HENRY; ROUGH J KIRKWOOD H

IC - (A) G01B-015/00 G01N-023/04 G01N-023/225 H01L-021/66

AP - JP2002322535 20021106 [2002JP-0322535]

PR - US88946092 19920527 [1992US-0889460]

ICAA - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]

ICCA - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]

FI - G01B15/00 B; G01N23/04; G01N23/225; H01L21/66 J; G01B15/00 K; G01B15/08

FTM - 2F067 AA45; 2F067 BB01; 2F067 CC17; 2F067 CC16; 2F067 HH06; 2F067 KK04; 2F067 KK08; 2F067 QQ02; 2F067 QQ12; 2F067 SS13; 2F067 SS02; 2F067 RR41; 2F067 RR29; 2F067 RR12; 2F067 RR07; 2F067 RR00; 2F067 QQ11; 2F067 PP12; 2F067 KK06; 2F067 JJ05; 2F067 FF14; 2F067 EE10; 2G001 AA03; 2G001 HA13; 2G001 JA03; 2G001 MA05; 2G001 LA11; 2G001 KA03; 2G001 JA12; 2G001 JA07; 2G001 JA02; 2G001 GA06; 2G001 BA07; 2G001 BA11; 2G001 CA03; 2G001 BA15; 4M106 AA20; 4M106 BA02; 4M106




AA09; 4M106 AA01; 4M106 BA03; 4M106 CA39; 4M106 DB05; 4M106 DB18; 4M106 DJ04; 4M106 DJ18; 4M106 DJ21

UP - 2003-34



---

5 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

PN -  US5578821 A 19961126 [US5578821]

STG - (A) United States patent

TI - (A) Electron beam inspection system and method

PA - (A) KLA INSTR CORP (US)

PA0 - KLA Instruments Corporation, San Jose CA [US]

IN - (A) MUNRO ERIC (GB); BRODIE ALAN D (US); DUTTA APRIL (US); EMGE DENNIS G (US); MCMURTRY JOHN (US); CHEN ZHONG-WEI (US); DESAI ANIL A (US); HONFI LESLIE A (US); MEISBERGER DAN (US); SIMMONS RICHARD (US); SMITH DAVE E A (US); PEARCE-PERCY HENRY (US); ROUGH J KIRKWOOD H (US)

IC - (A) H01J-037/00

AP - US37145895 19950111 [1995US-0371458]

PR - US37145895 19950111 [1995US-0371458]  
US88946092 19920527 [1992US-0889460]

ICAA - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]

ICCA - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]

EC - H01J-037/28  
H01J-037/30A2

PCL - ORIGINAL (O) : 250310000; CROSS-REFERENCE (X) : 250311000 250396000R  
250396000ML 250397000

DT - Basic

---

1 / 1 LEGALI - ©EPO

PN - US5578821 A 19961126 [US5578821]

AP - US37145895 19950111 [1995US-0371458]

ACT - 19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: KLA INSTRUMENTS CORPORATION 160 RIO ROBLES STREET;  
EFFECTIVE DATE: 19950526

19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: MEISBERGER, DAN; EFFECTIVE DATE: 19950526

19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: BRODIE, ALAN D.; EFFECTIVE DATE: 19950607

19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: DESAI, ANIL A.; EFFECTIVE DATE: 19950313

19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: EMGE, DENNIS G.; EFFECTIVE DATE: 19950327

19950728 US/AS02-A  
ASSIGNMENT OF ASSIGNOR'S INTEREST  
OWNER: CHEN, ZHO; EFFECTIVE DATE: 19950607

UP - 2003-22



---

6 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

PN - US5717204 A 19980210 [US5717204]  
STG - (A) United States patent  
TI - (A) Inspecting optical masks with electron beam microscopy  
PA - (A) KLA INSTR CORP (US)  
PA0 - KLA Instruments Corporation, San Jose CA [US]  
IN - (A) BRODIE ALAN D (US); CHEN ZHONG-WEI (US); JAU JACK Y (US);  
MEISBURGER DAN (US)  
IC - (A) H01J-037/26  
AP - US60685496 19960226 [1996US-0606854]  
PR - US60685496 19960226 [1996US-0606854]  
US25276394 19940602 [1994US-0252763]  
US88946092 19920527 [1992US-0889460]  
ICAA - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]  
ICCA - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]  
EC - H01J-037/28  
H01J-037/30A2  
PCL - ORIGINAL (O) : 250310000; CROSS-REFERENCE (X) : 250306000 250307000 250397000  
DT - Basic

---

1 / 1 LEGALI - ©EPO

PN - US5717204 A 19980210 [US5717204]  
AP - US60685496 19960226 [1996US-0606854]  
ACT - 20000502 US/RF-A  
REISSUE APPLICATION FILED  
EFFECTIVE DATE: 20000210

20000801 US/RF-A  
REISSUE APPLICATION FILED  
EFFECTIVE DATE: 20000210


20040907 US/RF-A  
REISSUE APPLICATION FILED  
EFFECTIVE DATE: 20040315

UP - 2004-38



---

7 / 7 PLUSPAT - ©QUESTEL-ORBIT - image

PN -  US5665968 A 19970909 [US5665968]  
STG - (A) United States patent  
TI - (A) Inspecting optical masks with electron beam microscopy  
PA - (A) KLA INSTR CORP (US)  
PA0 - KLA Instruments Corporation, San Jose CA [US]  
IN - (A) BRODIE ALAN D (US); CHEN ZHONG-WEI (US); GRENON BRIAN J (US); JAU  
JACK Y (US); MEISBURGER DAN (US)  
IC - (A) H01J-037/26  
AP - US60719196 19960226 [1996US-0607191]  
PR - US60719196 19960226 [1996US-0607191]  
US25276394 19940602 [1994US-0252763]  
US88946092 19920527 [1992US-0889460]  
ICAA - H01J-037/28 [2006-01 A - I R M EP]; H01J-037/30 [2006-01 A - I R M EP]  
ICCA - H01J-037/28 [2006 C - I R M EP]; H01J-037/30 [2006 C - I R M EP]  
EC - H01J-037/28  
H01J-037/30A2  
PCL - ORIGINAL (O) : 250310000; CROSS-REFERENCE (X) : 250306000 250307000  
DT - Basic

Search statement 2


---

[Top](#)

[Back](#)

Query/Command : prt ful legalall max

1 / 3 FAMPAT - ©QUESTEL-ORBIT - image

**FAN** - 20042780298181  
**PN** -  JP8068772 A 19960312 [JP08068772]  
           **STG:** Doc. Laid open to publ. Inspec.  
           **AP :** 1995JP-0126723 19950525  
**TI** - APPARATUS AND METHOD FOR AUTOMATIC MASK INSPECTION BY USING ELECTRON BEAM MICROSCOPY  
**PA** - KLA INSTR CORP  
**PA0** - (A) KLA INSTR CORP  
**IN** - DAN MAISUBAAGAA; ARAN DEII BUROODEII; TSUON UEI CHIEN; JIYATSUKU WAI JIYOO; BURAIAN JIEI GURENON  
**IN0** - DAN MEISBERGER; ALAN D BROADY; TSUON UEI CHIEN; JACK Y JOE; BRIAN J GLENNON  
**PR** - 1994US-0252763 19940602  
**IC** - G01M-011/00  
           G01N-023/20  
           G01N-023/203  
           G01N-023/22  
           G01N-023/225  
           G21K-005/04  
           H01J-037/28  
           H01L-021/66  
**ICAA** - G01M-011/00 [2006-01 A - I R M EP]; G01N-023/203 [2006-01 A - I R M EP]; G01N-023/225 [2006-01 A - I R M EP]; G21K-005/04 [2006-01 A - I R M EP]; H01J-037/28 [2006-01 A - I R M EP]; H01L-021/66 [2006-01 A - I R M EP]  
**ICCA** - G01M-011/00 [2006 C - I R M EP]; G01N-023/20 [2006 C - I R M EP]; G01N-023/22 [2006 C - I R M EP]; G21K-005/04 [2006 C - I R M EP]; H01J-037/28 [2006 C - I R M EP]; H01L-021/66 [2006 C - I R M EP]  
**FI** - G01N23/203; G01N23/225; G21K5/04 E; G01M11/00 T; H01L21/66 J; H01J37/28 C; H01J37/28 B; G03F1/08 S  
**FTM** - 2G001 AA03; 2G001 BA07; 2G001 BA15; 2G001 BA29; 2G001 CA03; 2G001 DA01; 2G001 FA06; 2G001 JA01; 2G001 JA15; 2G001 LA11; 2G001 RA03; 2G001 RA08; 2G001 RA20; 2G086 CC05; 2G086 GG01; 2G086 HH05; 2G086 HH06; 4M106 AA01; 4M106 AA09; 4M106 AA11; 4M106 BA02; 4M106 CA39; 4M106 CA41; 4M106 DE01; 4M106 DE08; 4M106 DE20; 4M106 DJ18; 4M106 DJ20; 4M106 DJ21; 5C033 UU01; 5C033 UU04; 5C033 UU05; 5C033 UU08; 2H095 BB03; 2H095 BD02; 2H095 BD14; 2H095 BA10; 2H095 BC16  
**CT** - (JP08068772)  
           [19] Citation as reason for refusal of an application  
           JP (A) 1990205762 [JP02205762]  
           JP (A) 1983119641 [JP58119641]  
           JP (A) 1993258703 [JP05258703]  
**AB** - (JP08068772)  
           PURPOSE: To automatically inspect a wafer, a X-ray mask, a substrate, etc., at a manufacturing site by providing an electronic beam generator to generate electronic beam.

Source: Legal > Federal Legal - U.S. > United States Code Service (USCS) Materials > United States Code Service - Titles 1 through 50

Copyright © 2007 by Matthew Bender & Company, Inc., a member of the LexisNexis Group. All rights reserved.

United States Code Service - Titles 1 through 50



☒ Terms and Connectors ☐ Natural Language

5717204 or 5,717,204

Search: ☒ Full-text of source documents

















Search [Advanced](#)

☐ Table of Contents (TOC) only

☐ Search Selected Only







[Clear All Selections](#) | [Hide Book Headers](#)

- ☒ ☐ TITLE 1. GENERAL PROVISIONS
- ☒ ☐ TITLE 2. THE CONGRESS
- ☒ ☐ TITLE 3. THE PRESIDENT
- ☒ ☐ TITLE 4. FLAG AND SEAL, SEAT OF GOVERNMENT, AND THE STATES
- ☒ ☐ TITLE 5. GOVERNMENT ORGANIZATION AND EMPLOYEES
- ☒ ☐ TITLE 6. DOMESTIC SECURITY
- ☒ ☐ TITLE 7. AGRICULTURE
- ☒ ☐ TITLE 8. ALIENS AND NATIONALITY
- ☒ ☐ TITLE 9. ARBITRATION
- ☒ ☐ TITLE 10. ARMED FORCES
- ☒ ☐ TITLE 11. BANKRUPTCY
- ☒ ☐ TITLE 12. BANKS AND BANKING
- ☒ ☐ TITLE 13. CENSUS
- ☒ ☐ TITLE 14. COAST GUARD
- ☒ ☐ TITLE 15. COMMERCE AND TRADE
- ☒ ☐ TITLE 16. CONSERVATION
- ☒ ☐ TITLE 17. COPYRIGHTS
- ☒ ☐ TITLE 18. CRIMES AND CRIMINAL PROCEDURE
- ☒ ☐ TITLE 19. CUSTOMS DUTIES
- ☒ ☐ TITLE 20. EDUCATION
- ☒ ☐ TITLE 21. FOOD AND DRUGS
- ☒ ☐ TITLE 22. FOREIGN RELATIONS AND INTERCOURSE
- ☒ ☐ TITLE 23. HIGHWAYS
- ☒ ☐ TITLE 24. HOSPITALS AND ASYLUMS
- ☒ ☐ TITLE 25. INDIANS
- ☒ ☐ TITLE 26. INTERNAL REVENUE CODE
- ☒ ☐ TITLE 27. INTOXICATING LIQUORS
- ☒ ☐ TITLE 28. JUDICIARY AND JUDICIAL PROCEDURE
- ☒ ☐ TITLE 29. LABOR
- ☒ ☐ TITLE 30. MINERAL LANDS AND MINING
- ☒ ☐ TITLE 31. MONEY AND FINANCE
- ☒ ☐ TITLE 32. NATIONAL GUARD
- ☒ ☐ TITLE 33. NAVIGATION AND NAVIGABLE WATERS
- ☒ ☐ TITLE 34. [NAVY]
- ☒ ☐ TITLE 35. PATENTS
- ☒ ☐ TITLE 36. PATRIOTIC AND NATIONAL OBSERVANCES, CEREMONIES, AND ORGANIZATIONS
- ☒ ☐ TITLE 37. PAY AND ALLOWANCES OF THE UNIFORMED SERVICES
- ☒ ☐ TITLE 38. VETERANS' BENEFITS
- ☒ ☐ TITLE 39. POSTAL SERVICE
- ☒ ☐ TITLE 40. PUBLIC BUILDINGS, PROPERTY, AND WORKS
- ☒ ☐ TITLE 41. PUBLIC CONTRACTS
- ☒ ☐ TITLE 42. THE PUBLIC HEALTH AND WELFARE


-   TITLE 43. PUBLIC LANDS
-   TITLE 44. PUBLIC PRINTING AND DOCUMENTS
-   TITLE 45. RAILROADS
-   TITLE 46. SHIPPING
-   TITLE 47. TELEGRAPHS, TELEPHONES, AND RADIOTELEGRAPHS
-   TITLE 48. TERRITORIES AND INSULAR POSSESSIONS
-   TITLE 49. TRANSPORTATION
-   TITLE 50. WAR AND NATIONAL DEFENSE

1 - 50 of 50

Key:

-  Click to expand level.\*
-  Click to collapse level.\*
-  Click to expand document subheadings.\*
-  Click to collapse document subheadings.\*
-  Click link to display full text of document.\*
-  Click to generate a TOC linking url.

\* Hover your cursor over this icon to display the Multiple Level Expand navigation menu.

Source: [Legal](#) > [Federal Legal - U.S.](#) > [United States Code Service \(USCS\) Materials](#) > **United States Code Service - Titles 1 through 50** 



LexisNexis®

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

## No Documents Found

No documents were found for your search terms

"5717204 or 5,717,204"

---

Click "Save this search as an Alert" to schedule your search to run in the future.

- OR -

Click "Edit Search" to return to the search form and modify your search.

### Suggestions:

- Check for spelling errors .
- Remove some search terms.
- Use more common search terms, such as those listed in "Suggested Words and Concepts"
- Use a less restrictive date range.

---

 Save this Search as an Alert

Edit Search



LexisNexis®

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

**LexisNexis® Total Research System**

Switch Client | Preferences | Feedback | Sign Off | Help

[My Lexis™](#)[Search](#)[Research Tasks](#)[Search Advisor](#)[Get a Document](#)[Shepard's®](#)[Alerts](#)[History](#) [Sources](#)[Guided Search Forms](#)[Command Searching](#)

**Combined Source Set 14**  - Intellectual Property Cases, Administrative Decisions & Regulations; Federal Register and CFR - Titles 19 and 37; Federal Register Documents Relating To Patent Issues; U.S. Patent & Trademark Office Decisions, Combined; Intellectual Property Law Review Articles, Combined; Patent, Trademark & Copyright Periodicals, Combined; Intellectual Property Law, Combined

**Enter Search Terms**
☒ Terms and Connectors   
 ☐ Natural Language   
 ☐ Easy Search

(5717204 or 5,717,204)

[Suggest Terms  
for My Search](#)
**Search** [Check Spelling](#)**Restrict by Document Segment:**

Select a document segment, enter search terms for the segment, then click Add.

[Select a Segment](#) [Add](#)

Note: Segment availability differs between sources. Segments may not be applied consistently across sources.

**Restrict by Date:**
☒ No Date Restrictions   
 ☐ From  To  [Date Formats...](#)
 **Search Help****Search Connectors**

and	and
or	or
w/N	within N words
pre /N	precedes by N words
w/p	in same paragraph
w/seg	in same segment
w/s	in same sentence
and not	and not
> More Connectors & Commands...	

**How Do I...?**

- > Use wildcards as placeholders for one or more characters in a search term?
- > Restrict by document segment?
- > Restrict by date?

[View Tutorials](#)

[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#)  
[History](#) | [Delivery Manager](#) | [Switch Client](#) | [Preferences](#) | [Feedback](#) | [Sign Off](#) | [Help](#)

**LexisNexis®**[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.



## LexisNexis® Total Research System

Switch Client | Preferences | Feedback | Sign Off | Help

[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#) | [History](#) | 

[Sources](#) | [Guided Search Forms](#) | [Command Searching](#)

**Combined Source Set 15**  - Federal & State Cases, Combined; Federal Court Cases, Combined; State Court Cases, Combined; U.S. Supreme Court Cases, Lawyers' Edition; U.S. Supreme Court Briefs; Federal Agency Decisions, Combined; State Administrative Codes & Registers, Combined

## Enter Search Terms

☒ Terms and Connectors ☐ Natural Language ☐ Easy Search

(5717204 or 5,717,204)

[Suggest Terms  
for My Search](#)

Search

Check Spelling

## Restrict by Document Segment:

Select a document segment, enter search terms for the segment, then click Add.

Select a Segment

Add

Note: Segment availability differs between sources. Segments may not be applied consistently across sources.

## Restrict by Date:

☒ No Date Restrictions ☐ From  To  [Date Formats...](#)

## Search Help

## Search Connectors

<u>and</u>	and
<u>or</u>	or
<u>w/N</u>	within N words
<u>pre /N</u>	precedes by N words
<u>w/p</u>	in same paragraph
<u>w/seg</u>	in same segment
<u>w/s</u>	in same sentence
<u>and not</u>	and not
> More Connectors & Commands...	

## How Do I...?

- > Use wildcards as placeholders for one or more characters in a search term?
- > Restrict by document segment?
- > Restrict by date?

[View Tutorials](#)
[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#)  
[History](#) | [Delivery Manager](#) | [Switch Client](#) | [Preferences](#) | [Feedback](#) | [Sign Off](#) | [Help](#)


LexisNexis®

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

## No Documents Found

No documents were found for your search terms

"(5717204 or 5,717,204)"

---

Click "Edit Search" to return to the search form and modify your search.

Suggestions:

- Check for spelling errors.
  - Remove some search terms.
  - Use more common search terms, such as those listed in "Suggested Words and Concepts"
  - Use a less restrictive date range.
- 

[Edit Search](#)



**LexisNexis®**

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

## LexisNexis™ Total Research System

Switch Client | Preferences | Feedback | Sign Off | ? Help

My Lexis™ | Search | Research Tasks | Search Advisor | Get a Document | Shepard's® | Alerts

History |

Sources | Guided Search Forms | Command Searching |

**Combined Source Set 15** - Federal & State Cases, Combined; Federal Court Cases, Combined; State Court Cases, Combined; U.S. Supreme Court Cases, Lawyers' Edition; U.S. Supreme Court Briefs; Federal Agency Decisions, Combined; State Administrative Codes & Registers, Combined

## Enter Search Terms

## Search Help

☒ Terms and Connectors   ☐ Natural Language   ☐ Easy Search

(5717204 or 5,717,204)

[Suggest Terms  
for My Search](#)

Search

Check Spelling

## Search Connectors

and	and
or	or
w/N	within N words
pre /N	precedes by N words
w/p	in same paragraph
w/seg	in same segment
w/s	in same sentence
and not	and not
> More Connectors & Commands...	

## How Do I...?

- > Use wildcards as placeholders for one or more characters in a search term?
- > Restrict by document segment?
- > Restrict by date?

[View Tutorials](#)

## Restrict by Document Segment:

Select a document segment, enter search terms for the segment, then click Add.

Select a Segment

Add

Note: Segment availability differs between sources. Segments may not be applied consistently across sources.

## Restrict by Date:

☒ No Date Restrictions ☐ From

To

[Date Formats...](#)

[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#)  
[History](#) | [Delivery Manager](#) | [Switch Client](#) | [Preferences](#) | [Feedback](#) | [Sign Off](#) | [Help](#)



LexisNexis™

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

**LexisNexis™ Total Research System**

Switch Client | Preferences | Feedback | Sign Off | [Help](#)

[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#)

[Sources](#) | [Guided Search Forms](#) | [Command Searching](#) | [History](#)

### Combined Source Set 1 - News, All (English, Full Text); Legal News Publications

Enter Search Terms

☒ Terms and Connectors   ☐ Natural Language   ☐ Easy Search

(5717204 or 5,717,204)

[Suggest Terms  
for My Search](#)
**Search**
[Check Spelling](#)

#### Restrict by Document Segment:

Select a document segment, enter search terms for the segment, then click Add.

**Add**

Note: Segment availability differs between sources. Segments may not be applied consistently across sources.

#### Restrict by Date:

☒ No Date Restrictions 

or

From

To

[Date Formats...](#)

### Search Help

#### Search Connectors

<a href="#">and</a>	and
<a href="#">or</a>	or
<a href="#">w/N</a>	within N words
<a href="#">pre /N</a>	precedes by N words
<a href="#">w/p</a>	in same paragraph
<a href="#">w/seg</a>	in same segment
<a href="#">w/s</a>	in same sentence
<a href="#">and not</a>	and not
> More Connectors & Commands...	

#### How Do I...?

- > Use wildcards as placeholders for one or more characters in a search term?
- > Restrict by document segment?
- > Restrict by date?

[View Tutorials](#)

[My Lexis™](#) | [Search](#) | [Research Tasks](#) | [Search Advisor](#) | [Get a Document](#) | [Shepard's®](#) | [Alerts](#)  
[History](#) | [Delivery Manager](#) | [Switch Client](#) | [Preferences](#) | [Feedback](#) | [Sign Off](#) | [Help](#)

**LexisNexis** [About LexisNexis](#) | [Terms & Conditions](#)  
 Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.

## No Documents Found

No documents were found for your search terms

**"(5717204 or 5,717,204)"**

---

Click "Edit Search" to return to the search form and modify your search.

Suggestions:

- Check for spelling errors.
  - Remove some search terms.
  - Use more common search terms, such as those listed in "Suggested Words and Concepts"
  - Use a less restrictive date range.
- 

[Edit Search](#)



LexisNexis

[About LexisNexis](#) | [Terms & Conditions](#)

Copyright © 2007 LexisNexis, a division of Reed Elsevier Inc. All rights reserved.